



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO.	REV. NO.
ATM-965	A
PAGE <u>1</u> OF <u>11</u>	
DATE 9 June 1971	

Presented in this ATM are the Lunar Mass Spectrometer (LMS) reliability prediction and mathematical models.

The A Revision herein has been updated to include the Lock Out Switching Circuit (page 11).

Prepared by: *F. Howell*
F. Howell
LMS Reliability P. E.

Approved by: *S. J. Ellison*
S. J. Ellison, Manager
ALSEP Reliability



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO. ATM-965	REV. NO. A
PAGE <u>2</u> OF <u>11</u>	
DATE 9 June 1971	

Introduction

Presented herein are the mathematical models and results of the updated numerical reliability analysis as performed on the Lunar Mass Spectrometer. Two types of logic are presented, one type for before experiment deployment, and the other type for after experiment deployment. The former considers all elements as serially connected while the later excludes those elements whose final function is executed during deployment and also provides for degraded mode analysis.

Results

Table I presents a summary of the results of this analysis.

Assumptions

The following assumptions were applied to the numerical reliability analysis herein:

- 1) Operating temperature of the electronic parts are in accordance with Table II.
- 2) Derating factors are in accordance with ATM 241E.
- 3) Failure rates were developed from ATM 605 Rev A.
- 4) Expected semiconductor or integrated circuit junction thermal rises were extrapolated from "ALSEP, Array E Electronic Packaging Thermal Design Guidelines, " Letter No. 9712-101.
- 5) Probability of success was calculated through the mathematical formulation

$$R = e^{-\lambda t}$$

where

R is the probability of success

λ is the electronic component part failure rate given in
%/1000 hours

t is the mission or storage time



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO.	REV. NO.
ATM-965	A
PAGE 3	OF 11
DATE 9 June 1971	

- 6) The dormant or storage failure rate was calculated as follows:

Active Failure Rate X 0.01

- 7) The transient failure rate (non-operating from Launch to Experiment deployment) was calculated as follows:

Active Failure Rate X 0.1

- 8) The storage time used in the mathematical models was two years or 17,520 hours.
- 9) The transient time used in the mathematical models was 109 hours.
- 10) The mission time used in the mathematical models was two years or 17,520 hours.
- 11) Degraded Modes were defined by expansion of (R+Q)³ reference "Lunar Mass Spectrometer Reliability Block Diagram" (After Experiment Deployment).
- 12) Junction temperatures for discrete devices (transistors and semiconductors) were normalized in accordance with MIL-HDBK 217A and ATM 605A tables as follows:

$$\theta_{J-A} = \frac{T_{J \max} - T_S}{P_{J \max}}$$

where

θ_{J-A} is thermal resistance from junction to circuit board (°C/W)

$T_{J \max}$ is the maximum rated temperature (°C)

T_S is the ambient temperature, 25°C

$P_{J \max}$ is the maximum power rating for the device (watts)



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO.	REV. NO.
ATM-965	A
PAGE <u>4</u>	OF <u>11</u>
DATE 9 June 1971	

$$T_j = T_a + (\theta_{J-A}) P_j$$

where:

T_j is the actual junction temperature in the application or design.

T_A is the actual ambient temperature at the circuit board in °C.

θ_{J-A} is the thermal resistance from junction to the circuit board in °C/watt.

P_j is the average power dissipated (watts in the circuit application or design).

13) It is to be noted that the reliability prediction herein reflects the results of the component application analysis and not the failure modes and effects analysis.

14. Loading of 54L and 54 series I. C. 's:

The "limiting parameter" loading must be followed when determining the maximum fan out for a device. This is summarized in T.I. 's catalog CC201-R pages 12-1 through pages 12-3.

To summarize the tables:

- 1) A 54 series loaded by a 54 series: $N = 10$ where $N = 1$ is -1.6 Ma (limiting parameter).
- 2) A 54L series loaded by a 54L series: $N = 10$ where $N = 1$ is $-.18$ Ma limiting parameter).

The above values must be derated in accordance with ATM 241E to 75 percent. This limits the TTL devices to:

- 1) A 54 series may be loaded with as many as seven 54 series single inputs or thirty-two 54L series single inputs.



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO. ATM-965	REV. NO. A
PAGE <u>5</u> OF <u>11</u>	
DATE 9 June 1971	

- 2) A 54L series may be loaded with as many as seven 54L series single inputs or one 54 series single input.

Under no circumstances may a circuit be loaded over 80%.

Conclusions

Section I - The overall reliability goal for the Lunar Mass Spectrometer is .90. The Reliability prediction for two years operation on the lunar surface using failure rates from the Parts Application Analysis, is .858. This value is increased to .876 when using the Q values from the Failure Modes and Effect Analysis.

8

7

6

5

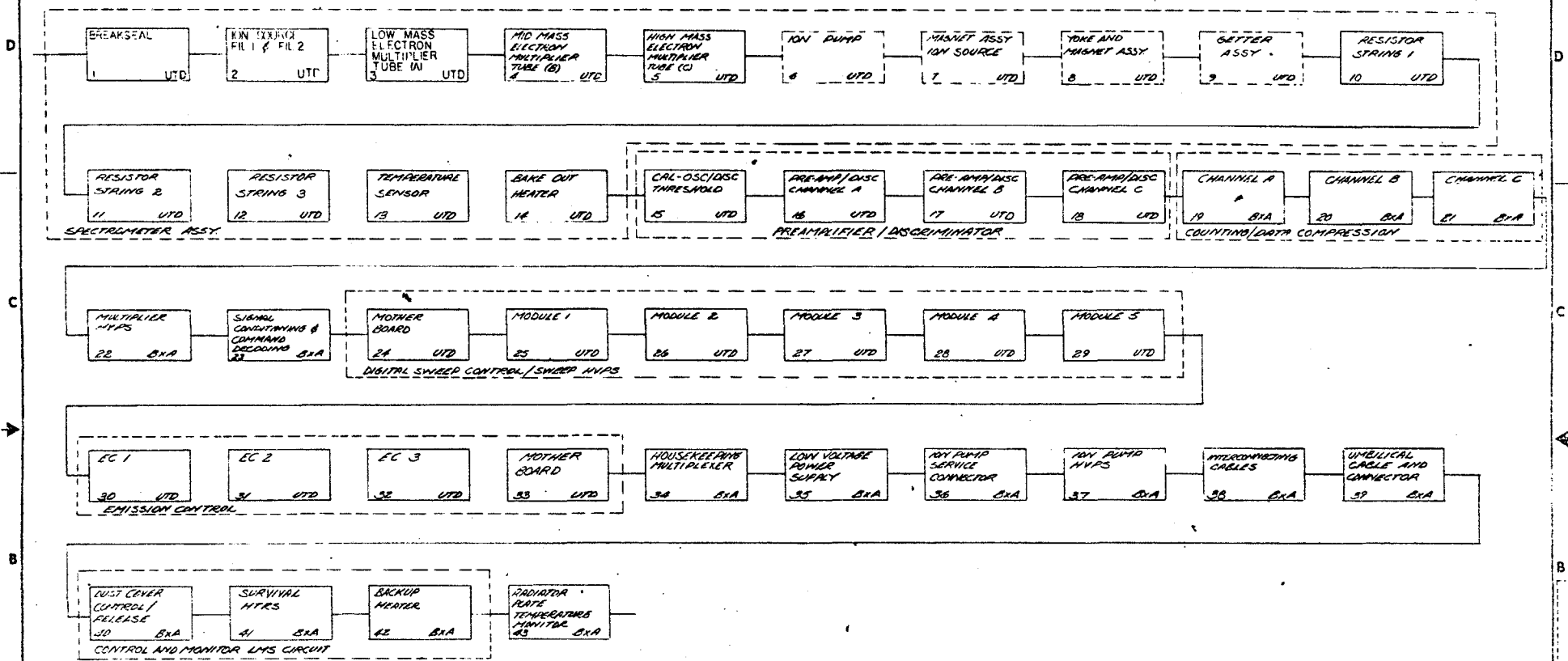
4

3

2

1

RELIABILITY		REVISIONS		CONF. NO.
APPROX. PROBABILITIES	TIME LTR.	DESCRIPTION	DATE	APPROX. 2
7.7E-7				



NOTES
 1 TIME INTERVAL FOR THIS DIAGRAM IS FROM AIA THROUGH EXPERIMENT DEPLOYMENT
 2 MATHEMATICAL MODEL FOR THE PROBABILITY OF EXPERIMENT SUCCESS BEFORE EXPERIMENT DEPLOYMENT

$$R_T = \frac{R_5}{R_1} \cdot \frac{R_2}{R_1} \cdot \frac{R_3}{R_1} \cdot \frac{R_4}{R_1}$$

PROPERTY NOTES
 THIS DRAWING CONTAINS UNCLASSIFIED INFORMATION TO THE BENDIX CORPORATION AND IS NOT TO BE RELEASED OR DISSEMINATED OUTSIDE THE BENDIX CORPORATION WITHOUT THE EXPRESS WRITTEN PERMISSION OF THE BENDIX CORPORATION.

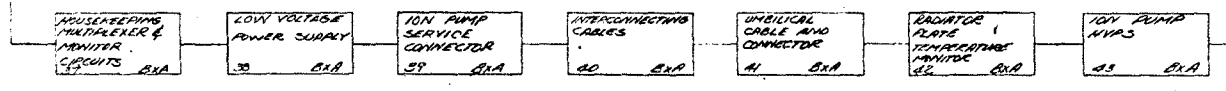
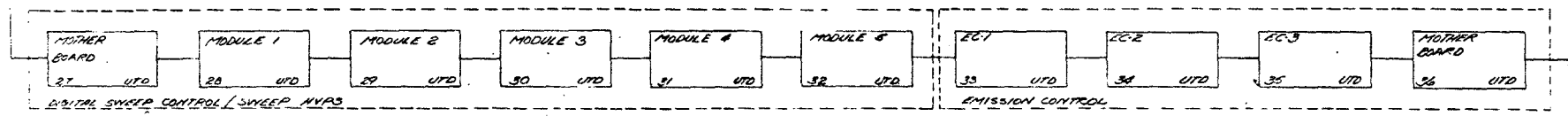
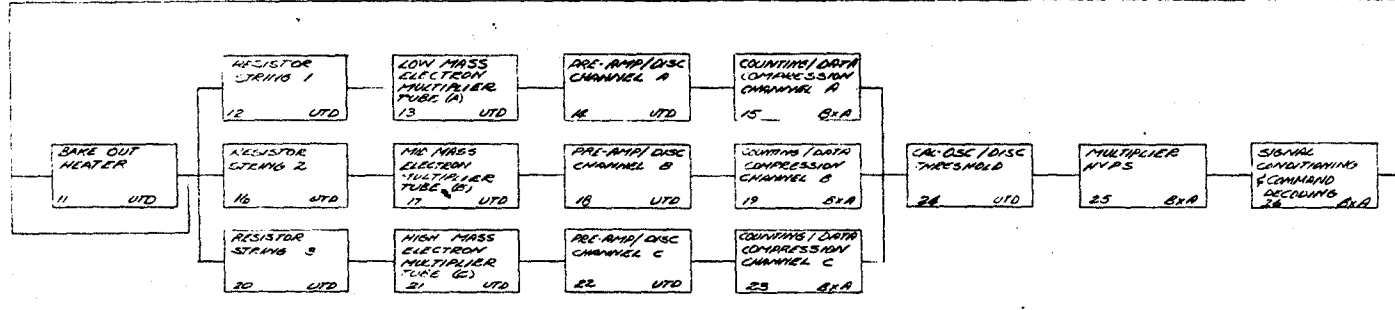
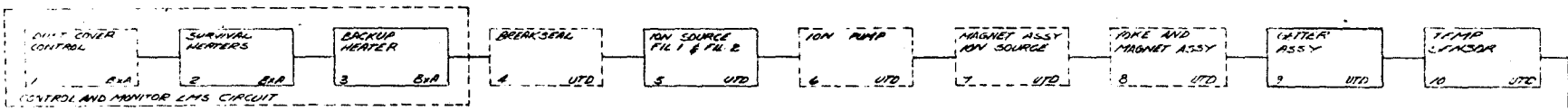
REV	DESCRIPTION	CODE	PART OR SPECIFICATION NO.	ITEM
1				

UNLESS OTHERWISE SPECIFIED:		CONTR. NO.	
DIMENSIONS ARE IN INCHES	TOLERANCES	DRAWN	BY: <i>[Signature]</i>
DECIMAL	ANGLES	CHECKED	
.1	°	DESIGN BY	
.01	'	DESIGN SUPV.	
.005	"	PROJ. ENGR.	
SURFACE FINISH	CHARACTER # 95	QUAL. CONT.	
MICROINCHES RMS		REV. DATE	
MATERIAL:		CSGN. APPL.	
		BY:	
		CUSTOMER	

LIST OF MATERIALS	
THE BENDIX CORPORATION	
AEROSPACE SYSTEMS DIVISION - AMB BLDG., SICKLEBAR	
TITLE	
LOW MASS SPECTROMETER	
RELIABILITY BLOCK DIAGRAM	
(BEFORE EXPERIMENT DEPLOYMENT)	
SIZE CODE	IDENT NO. (OPTIONAL NUMBER)
D	07038
SCALE	1:1
SHEET	6 OF 7

RELIABILITY		REVISIONS		DATE	
APPD	PREDICTION	ZONE	ITER	DESCRIPTION	DATE
744	6-3-71				

1. 100% INSPECTION FOR THIS EQUIPMENT IS AFTER EQUIPMENT DEPLOYMENT
 2. ALL ION SOURCE ASSEMBLY 5, 7 & 9 ARE EXCLUDED FROM THE MANUFACTURING
 3. ALL ION SOURCE ASSEMBLY 5, 7 & 9 ARE EXCLUDED FROM THE MANUFACTURING
 4. ALL ION SOURCE ASSEMBLY 5, 7 & 9 ARE EXCLUDED FROM THE MANUFACTURING
 5. ALL ION SOURCE ASSEMBLY 5, 7 & 9 ARE EXCLUDED FROM THE MANUFACTURING



PROPRIETARY NOTICE
 THIS DRAWING CONTAINS INFORMATION PROPRIETARY TO THE BENDIX CORPORATION AND/OR ITS VENDORS AND SUPPLIERS. THIS DRAWING MAY NOT BE DISCLOSED TO OTHERS FOR ANY PURPOSE NOR USED FOR MANUFACTURING PURPOSES WITHOUT THE WRITTEN PERMISSION OF THE BENDIX CORPORATION.

PART NO.	REV. ASST.	END ITER NO.	SERIAL NO.

UNLESS OTHERWISE SPECIFIED:
 DIMENSIONS ARE IN INCHES
 TOLERANCES
 ANGLES
 SURFACE FINISH
 MICROINCHES RMS

QTY REQD	DESCRIPTION	CODE	PART OR SPECIFICATION NO.	ITER

DATE	BY	CHECKED BY	DESIGNED BY	PROJ. ENGR.	DATE	BY

THE BENDIX CORPORATION	AEROSPACE SYSTEMS DIVISION - ANN ARBOR, MICHIGAN
TITLE	LOW MASS SPECIFICATIONS
SIZE	CODE IDENT NO. DRAWING NUMBER
D	07038
SCALE	DATE
	SHEET 7 OF 11

RELIABILITY		REVISIONS			CONFIG DST.
APPR	PREDICTION	ZONE	LTR	DESCRIPTION	DATE
7/11	6-3-71				
					APPLY'D

NOTES (CONT)

6. MATHEMATICAL MODELS

FATH	CHANNELS WORKING	CHANNELS FAILING	MATH MODEL FOR EXPERIMENT WITH DEGRADED MODE	MATH MODEL FOR EXPERIMENT RELIABILITY WITH NORMAL OPERATION
1	A	B, C	$\frac{R_1}{\pi R_2} [1 - (R_1 R_2 R_3 R_4 R_5)] [1 - (R_6 R_7 R_8 R_9)]$	
2	B	A, C	$\frac{R_1}{\pi R_2} [1 - (R_2 R_3 R_4 R_5)] [1 - (R_6 R_7 R_8 R_9)]$	
3	C	A, B	$\frac{R_1}{\pi R_2} [1 - (R_2 R_3 R_4 R_5)] [1 - (R_6 R_7 R_8 R_9)]$	
4	A, B	C	$\frac{R_1}{\pi R_2} [1 - (R_3 R_4 R_5 R_6 R_7)]$	
5	AC	B	$\frac{R_1}{\pi R_2} \frac{R_3}{R_4} [1 - (R_2 R_3 R_4 R_5)]$	
6	AC	A	$\frac{R_1}{\pi R_2} [1 - (R_2 R_3 R_4 R_5)]$	
7	A, B, C	NO FAILURE		$\frac{R_1 R_2 R_3 R_4 R_5}{R_6}$

7. REFERENCE PARA 6: FATH 7 DETERMINE THE PROBABILITY OF SUCCESS FOR THE LMS DURING OPERATION FOR TWO YEARS ON THE LUNAR SURFACE. THE REMAINING FATHS ARE TO BE USED TO SUPPORT RELIABILITY TRADE OFF STUDIES AND OPTIMIZATION OF THE CIRCUIT DESIGNS.
8. TO DETERMINE TOTAL EXPERIMENT RELIABILITY WITH DEGRADED MODE(S), ADD FATH 7 AND THE DESIRED FATH(S), 1 TO 6.

QTY REQD	DESCRIPTION	CODE IDENT	PART OR SPECIFICATION NO.	ITER

PROPRIETARY NOTICE
 THIS DRAWING CONTAINS INFORMATION PROPRIETARY TO THE BENDIX CORPORATION AND/OR ITS VENDORS AND SUPPLIERS. THIS DRAWING MAY NOT BE DISCLOSED TO OTHERS FOR ANY PURPOSE NOR USED FOR MANUFACTURING PURPOSES WITHOUT THE WRITTEN PERMISSION OF THE BENDIX CORPORATION.

UNLESS OTHERWISE SPECIFIED: DIMENSIONS ARE IN INCHES			
TOLERANCES			
DECIMAL	ANGLES		
.X	*	*	
.XX	*	*	
.XXX	*	CHAMFER $\alpha 5^\circ$	
SURFACE FINISH MICROINCHES RMR			
DRAWING CLASS		FINISH	
A	B	C	

LIST OF MATERIALS			
THE BENDIX CORPORATION AEROSPACE SYSTEMS DIVISION - ANN ARBOR, MICHIGAN			
CONTR NO.	TITLE		
DRAWN <i>2/11/71</i>	LUNAR MASS SPECTROMETER RELIABILITY BLOCK DIAGRAM (AFTER EXPERIMENT DEPLOYMENT)		
CHECKED	STRESS/WT	DSGN SUPV	PROJ ENGR
QUAL CONT	STS. SPT.	DSGN APPL	WFG
CUSTOMER	SCALE	WEIGHT	SHEET 8 of 11

RELIABILITY		REVISIONS		DATE	APPROV
APPROX PREDICTION	CODE LTR	DESCRIPTION	DATE	APPROV	
754	6.3.77				

TABLE I
LMS RELIABILITY SUMMARY

LOGIC NO. BEFORE DEPLOY	LOGIC NO. AFTER DEPLOY	EQUIPMENT	λ OPERATE #/1000 HRS	λ STORAGE #/1000 HRS	RELIABILITY PIA TO LAUNCH 2 YR STORAGE 6-17,320 HRS	RELIABILITY FROM LAUNCH TO DEPLOYMENT 6-109 HRS	RELIABILITY FOR TWO YEAR MISSION AFTER DEPLOYMENT								RELIABILITY AFTER PIA THROUGH 2 YR OPERATION	
							UTD OPERATION	B/A OPERATION	COMPLETE OPERATION A,B,C	DEGRADED OPERATION				B,C,A		
							A,B,C	B,A,E	C,A,B	A,B,E	A,C,B	B,C,A				
38	40	INTER CONNECTING CABLES	.003620	.0000362	.999999	.999999		.999966	.999966							.999960
39	41	UMBILICAL CABLE AND CONNECTOR	.000008	.00000008	.999999	.999999		.999999	.999999							.999997
		CONTROL MONITOR	.002070	.000821	.999856	.999991		.985783	.985733							.985582
40	1	DET CONGR CONTROL	.020918	.002209	.999963	.999996		.999999	.999999							.996303
41	2	SURVIVAL HEATER	.028808	.000308	.999932	.999996		.999999	.999999							.995152
42	3	BACKUP HEATER	.002366	.000223	.999981	.999996		.996093	.996083							.996052
43	42	RADIATOR PLATE TEMP MONITOR	.003600	.000003	.999995	.999999		.999474	.999474							.999468
	***	TOTAL UTD A OPERATE														
		TOTAL B/A A OPERATE														
		TOTAL UTD RELIABILITY					.987105									
		TOTAL B/A RELIABILITY						.905648								
		TOTAL LMS 2 YR OP AFTER DEPLOY ONLY							.857715							
		TOTAL LMS A,B,C AFTER DEPLOY ONLY								.858067						
		TOTAL LMS B,A,C AFTER DEPLOY ONLY									.858067					
		TOTAL LMS C,A,B AFTER DEPLOY ONLY										.875936				
		TOTAL LMS A,B,E AFTER DEPLOY ONLY											.875936			
		TOTAL LMS B,C,A AFTER DEPLOY ONLY												.875936		
		TOTAL LMS AFTER PIA THRU 2 YR OPERATION														.856218

*** OPERATING TIME, 5 HRS
*** EXCLUDES ION PUMP FAILURE RATE

PROPRIETARY NOTICE
THIS DRAWING CONTAINS INFORMATION PROPRIETARY TO THE BENDIX CORPORATION AND/OR ITS VENDORS AND SUPPLIERS. THIS DRAWING MAY NOT BE DISCLOSED TO OTHERS FOR ANY PURPOSE AND USED FOR MANUFACTURING PURPOSES WITHOUT THE WRITTEN PERMISSION OF THE BENDIX CORPORATION.

QTY REQD	DESCRIPTION	CODE IDENT	PART OF SPECIFICATION NO.	UNIT
LIST OF MATERIALS				
CONTR NO. THE BENDIX CORPORATION				
DRAWING NO. AEROSPACE SYSTEMS DIVISION - ANN ARBOR, MICHIGAN				
REGIONAL	ANGLES	TOLERANCES	TITLE	
STRESS WT				
DISN SUPPLY				
PROJ ENGR				
EQUAL CONC				
SIZE	CODE IDENT NO.	DRAWING NUMBER		
D	07038			
SCALE	INCHES			



**Aerospace
Systems Division**

LUNAR MASS SPECTROMETER
RELIABILITY PREDICTION

Contract No. NAS 9-5829

NO.	REV. NO.
ATM - 965	A
PAGE 11	OF 11
DATE 15 July 1971	

Lock Out Switch

This switch was added to prevent accidental turn on of the ion source filaments (numbers 1 or 2) during ground test when the chamber is back filled with argon. The switch is mounted on the base plate and is a normally closed switch. The switch, when activated, will open the +29 volt supply to the emission control inverter circuit. The switch is activated by a pin inserted through the base plate from outside the LMS. The pin is "flaged" DO NOT FLY and will be removed after final test. The switch will also be hard wired for a short circuit prior to flight.

For the reason that the switch is to be hard wired and shorted out before flight, the reliability of this switch will not effect the reliability of the LMS.

The switch is controlled by BxA SCD number 2346242-1. The Emission Control Schematic number is 151-702. The circuit is shown below.

